Review of birefringence study in KAGRA

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Sapphire test masses for KAGRA

In KAGRA, the four test masses are sapphire. Other optics are fused silica, e.g., BS, IMC, PRMs and SRMs.

- High thermal conductivity
- Low absorption at cryogenic temperature
- Good optical properties at 1064nm
- However, sapphire is birefringent.

$$n_o = 1.754$$
 $n_e = 1.747$ $\Delta n = 0.007$





The beam propagation is aligned with the c-axis (no birefringence).

But the inhomogeneity of the substrate (mainly ITMs) will create birefringence.

Birefringence issues in the interferometer



Sapphire test masses

Birefringence mainly comes from ITM substrates.

- Loss in beam power (reduce sensitivity)
- The p-pol can have a bad consequence to length control and alignment control system.
- The amount of birefringence is not balanced between the arms, which leads to additional laser intensity/frequency noises

Current situation JGW-G2012374



Analytical description for birefringence

Birefringence coupling in ITM substrate





Considering the incident beam is pure s-pol. It is projected to e-axis and o-axis. After a propagation of thickness d, the two fields are

$$E_e = S_{in} \cos \phi \, e^{i\alpha_e} \qquad E_o = S_{in} \sin \phi \, e^{i\alpha_o}$$

The two fields are then projected back to s-pol axis and p-pol axis:

$$E_{s \to s} = \cos \theta E_e + \sin \theta E_o = S_{in} (\cos^2 \theta e^{i\alpha_e} + \sin^2 \theta e^{i\alpha_o})$$

= $S_{in} e^{i\alpha_+} (\cos^2 \theta \cdot e^{i\alpha_-} + \sin^2 \theta \cdot e^{-i\alpha_-})$
 $E_{s \to p} = \sin \theta E_e - \cos \theta E_o = S_{in} (\sin \theta \cos \theta e^{i\alpha_e} - \sin \theta \cos \theta e^{i\alpha_o})$
= $S_{in} e^{i\alpha_+} \cdot i \sin 2\theta \sin \alpha_-$

Similarly, if the input beam is pure p-pol,

$$E_{p \to s} = P_{in} e^{i\alpha_{+}} \cdot i \sin 2\theta \sin \alpha_{-}$$
$$E_{p \to p} = P_{in} e^{i\alpha_{+}} (\sin^{2}\theta \cdot e^{i\alpha_{-}} + \cos^{2}\theta \cdot e^{-i\alpha_{-}})$$

$$\boldsymbol{M}(\boldsymbol{\theta}, \boldsymbol{\alpha}_{-}) = e^{i\alpha_{+}} \begin{pmatrix} \cos^{2}\boldsymbol{\theta} \cdot e^{i\alpha_{-}} + \sin^{2}\boldsymbol{\theta} \cdot e^{-i\alpha_{-}} & i\sin 2\boldsymbol{\theta} \sin \alpha_{-} \\ i\sin 2\boldsymbol{\theta} \sin \alpha_{-} & \sin^{2}\boldsymbol{\theta} \cdot e^{i\alpha_{-}} + \cos^{2}\boldsymbol{\theta} \cdot e^{-i\alpha_{-}} \end{pmatrix}$$

Transmission of a linearly polarized light through a birefringent medium:

Input beam
$$V = \begin{pmatrix} S_{in} \\ P_{in} \end{pmatrix}$$
 Output beam $V' = MV$

M is the Jones matrix of the substrate



TWE measurements with Fizeau interferometer

Transmission wavefront error (TWE) maps of TMs are measured with Fizeau interferometer before installation.

If we take 4 measurements by rotating the polarization of the input beam

 $P_{out}(\theta + 0) = 1 + A^2 + 2A\cos 2\theta \sin 2\alpha_ P_{out}(\theta + 45) = 1 + A^2 - 2A\sin 2\theta \sin 2\alpha_ P_{out}(\theta + 90) = 1 + A^2 - 2A\cos 2\theta \sin 2\alpha_ P_{out}(\theta + 135) = 1 + A^2 + 2A\sin 2\theta \sin 2\alpha_-$





Measure TWE with different input polarization directions

ne





By combining several TWE maps with different orientation of the beam polarization, we can extract θ and α_{-} : <u>JGW-T1910380</u>

$$\theta = -\frac{1}{2} \tan^{-1} \frac{TWE(45) - TWE(135)}{TWE(0) - TWE(90)}$$
$$\alpha_{-} = \frac{2\pi}{\lambda} \cdot \frac{TWE(0) - TWE(90)}{\cos 2\theta}$$



Characterization of TWE maps

TWE maps are measured before birefringence problem is realized.

- The setup was not optimized for birefringence study.
- We hope to rotate the input polarization rather than the mirror.
- We don't know how much errors are there in the TWE maps.
 - Piston: unknown
 - Tilt: unknown
 - Curvature: can be removed
 - Astigmatism: can be removed

Our method is easily affected by TWE measurement errors.

$$\theta = -\frac{1}{2} \tan^{-1} \frac{TWE(45) - TWE(135)}{TWE(0) - TWE(90)}$$

Errors are amplified when denominator is zero.

Theta needs to be unwrapped.





Rotation angle calibration

astigmatism of reference sphere

Parameter scan for piston

$$\theta = -\frac{1}{2} \tan^{-1} \frac{TWE(45) - TWE(135) + X}{TWE(0) - TWE(90) + Y}$$





0.1

0.08

0.06

0.04

0.02

0

-0.02

-0.04

-0.06

-0.08

-0.1

Expand the map to one-dimension and calculate the "roughness".

$$\mathcal{R} = \sum_{k=1}^{n-1} (x_{k+1} - x_k)^2$$



Parameter scan for piston



ITMY



150 4500 4000 100 3500 50 3000 X O Y O Y [nm] 2500 Z 4415.08 0 2000 -50 1500 1000 -100 500 -150 -150 -100 -50 0 50 100 150 X [nm]



2 4 6

-6 -4

-2 0

x [cm]



x [cm]





Remove roughness above 4500













Modeling birefringence



Finesse is considering to add birefringence features but for now we have to use the *two-world approach*.



Motivation of simulation:

To understand the influence of the birefringence of sapphire mirrors in the cryogenic interferometer and to find ways of mitigating the birefringence effect.

- Help with the commissioning
- Resonance condition and gain in PRC
- Signal degeneracy in alignment control
- scattering effects of both beams in s-polarization and p-polarization.
- Imbalance at the AS port.



The key of the two-world approach is to define a birefringent component that defines the coupling between s-pol and p-pol light.

A model representing birefringence couplings



We need to apply reflectivity maps to the two beamsplitters and phase maps to the two steering mirrors in the MZ model.

We are using FINESSE for birefringence simulation, as FINESSE is capable simulating mirror defects using realistic mirror maps.



Intuitive understanding of the MZ model:

- Reflectivity and transmissivity of the first beamsplitter represent projections of the input linearly polarized light along o-axis and e-axis.
- The o-light and e-light accumulate different phase delays along their paths, combined and projected back to s/p axis at the second beamsplitter.

Future simplified model



 $E_{s \to s} = rE_{in}e^{i(\alpha_{+}+\psi)}$ $E_{s \to p} = itE_{in}e^{i\alpha_{+}}$

Parameter that we need are θ , α_+ , α_- .

Single arm cavity reflection



The p-pol power reflected by the cavity is smaller than the single bounce reflection power by the ITM due to Lawrence effect.



Supposing mode matched

Round-trip single bounce p-pol power: $ho_{
m rt}$

One way p-pol TEM00 percent: β

Mode content of p-pol



TEM00: <10% 1st mode: ~20% 2nd mode: ~10% Higher order: >60%

Lawrence effect (mode healing effect)

- The effect of TWE(ϕ) at reflection is strongly cancelled for TEM00.
- In other words, at cavity reflection, HOMs introduced by ITM distortion are strongly suppressed.

$$r_{\text{cav}} = 1 - \frac{2T_1}{T_1 + T_2 + \mathcal{L}} \qquad r_{\text{cav}}^2 = 0.937$$
$$r_{\text{LE}} = 1 - \frac{T_1}{T_1 + T_2 + \mathcal{L}} \qquad r_{\text{LE}}^2 = 0.00022$$

Reflected power:

$$P_4 \approx \rho_{\rm rt} \beta r_{\rm cav}^2 + \rho_{\rm rt} (1-\beta) r_{\rm LE}^2$$
$$S_4 \approx r_{\rm cav}^2 - \rho_{\rm rt} \beta r_{\rm cav}^2 - \rho_{\rm rt} (1-\beta) r_{\rm LE}^2$$



Simulation without mirror map

Fixed parameter simulation without realistic mirror map

ROC and tilt x to	P-pol power	P-pol mode content (one-way)			
create different modes	Round-trip P4	TEM00	TEM01	TEM02	
Model 1	5%	10%	79.6%	10.4%	
Model 2	5%	30%	40.9%	29.1%	
Model 3	5%	50%	1.4%	48.6%	

P-pol single bounce reflection from ITM



P-pol reflected by arm cavity



Arm cavity round-trip loss simulation

P-pol reflection

Laser frequency

-100

-50

No p-pol

50

5% p-pol [10% 00]

5% p-pol [30% 00] 5% p-pol [50% 00]

100

150



Reflected power in s-pol and p-pol [W]

P-pol	Calculation		Simul	Simulation		Round-trip loss (ppm)	
content	S-pol	P-pol	S-pol	P-pol	S + P	Only S	
Model 1	0.9325	0.0047	0.9318	0.0068	61.5	19.2	
Model 2	0.9231	0.0141	0.9199	0.0184	61.9	31.8	
Model 3	0.9137	0.0234	0.9102	0.0277	62.2	42.0	

Input power is assumed to be 1 W.

We suppose the cavity has 60 ppm round-trip loss.

Round-trip loss measurement process JGW-T2011633, LIGO-G1501547, LIGO-T1700117



Round-trip loss can be derived from the equation:

 $\mathcal{L} = \frac{T_1}{4\eta} \left(1 - \frac{P_l}{P_m} + T_1 \right) \qquad \eta : \text{mode matching ratio}$

- When there is birefringence, the beam power reflected by the cavity will change.
- The round-trip loss measurement is not accurate anymore if we only measure s-pol beam.
- We also need to consider BS reflectivity imbalance for s-pol and p-pol.

Simulation for single arm alignment sensing signal



PDH error signal when scanning arm cavity



0.6

0.8

1.0

le-6

Fixed parameter simulation without realistic mirror map

ROC and tilt x to	P-pol power	P-pol mode content (one-way)			
create different modes	Round-trip P4	TEM00	TEM01	TEM02	
Model 1	5%	10%	79.6%	10.4%	
Model 2	5%	30%	40.9%	29.1%	
Model 3	5%	50%	1.4%	48.6%	

When tuning alignment of the cavity, the cavity is locked via s-pol PDH error signal.



S-pol ASC error signal of single arm cavity



Some simple calculations

 $S_{OPD} \sim u_{-}^* u_1 + u_{+} u_1^*$

Some assumptions:

- RF sidebands power: 2%
- Single bounce birefringence power: 5% (1st order mode content 20%)



$$S_{QPD} \sim \frac{u_{-}^{*}u_{1} + u_{+}u_{1}^{*}}{2\%^{*}1\%} + \frac{u_{0}^{*}u_{1-} + u_{0}u_{1+}^{*}}{97\%^{*}2\%^{*}5\%^{*}20\%}$$

The ASC offset error mainly comes from the beat between the fundamental mode and 1st mode from RF sidebands due to birefringence.

Can we improve the ASC signal by combining s + p signal?



It is obvious $(u_{-}^{*}u_{1})_{s+p} \neq (u_{-}^{*}u_{1})_{s} + (u_{-}^{*}u_{1})_{p}$

How can we improve the ASC signal when there is birefringence?

- New ASC control scheme?
- Compensating the offset introduced by birefringence?
 - Digital signal processing?
 - Mapping the offset?
 - Monitoring the mode contents of p-pol?

Cavity round-trip loss (ppm)				
	90% mode matching	95% moo matchin		

	90% mode matching	95% mode matching
Measurement 1	317.2	300.5
Only S-pol	271.9	257.6
Measurement 2	342.6	324.5
Only S-pol	309.5	293.1

Cavity round-trip loss (ppm)

	90% mode matching	95% mode matching
Measurement 1	118.8	112.6
Only S-pol	0.44	0.42
Measurement 2	99.2	93.9
Only S-pol	-22	-21.3

	S-pol power Camera	P-pol power Camera	S-pol power Calibrated	P-pol power Calibrated	P-pol percentage
X unlocked 1	6750.0	859.6	13500.0	1074.5	7.4%
X unlocked 2	6800.0	886.5	13600.0	1108.1	7.5%
X locked 1	5125.0	177.6	10250.0	222.0	2.1%
X locked 2	4933.3	292.7	9866.6	365.9	3.6%

	S-pol power Camera	P-pol power Camera	S-pol power Calibrated	P-pol power Calibrated	P-pol percentag
Y unlocked 1	7250.0	484.9	14500.0	2424.5	14.3%
Y unlocked 2	7163.74	468.12	14327.48	2340.6	14.0%
Y locked 1	7276.1	126.0	14552.2	630	4.1%
Y locked 2	7337.88	114.29	14675.76	571.45	3.7%

Single bounce from ITM (arm cavity unlocked)



ITMX

P-pol

S-pol



Measurement 1



POP_Ppol At 2022-08-11-06-13-13 UTC X center: 274-6 Y center: 246-2

POP_PpolAt 2022-08-15-02-19-54 UTC X center: 290-4 Y center: 252-5

ITMY

Measurement 2



Single bounce from ITMX

Total



ITMX





Measurement (August)





Measurement (March)



S-pol

P-pol







-0.08 -0.1 -0.1

-0.05

0.05

0.1

Single bounce from ITMY





100



Thank you!

S-pol loss estimation



- Loss estimation 2.5% (2.3%~2.7% with 0.5cm decenter) Measurement 6.1%
- We have installed some polarization optics in KAGRA and are going to take more precise measurements for birefringence loss.



 $\boldsymbol{M}(\boldsymbol{\theta},\boldsymbol{\alpha}_{-}) = \begin{pmatrix} \cos^{2}\boldsymbol{\theta} \cdot e^{i\boldsymbol{\alpha}_{-}} + \sin^{2}\boldsymbol{\theta} \cdot e^{-i\boldsymbol{\alpha}_{-}} & i\sin 2\boldsymbol{\theta}\sin \boldsymbol{\alpha}_{-} \\ i\sin 2\boldsymbol{\theta}\sin \boldsymbol{\alpha}_{-} & \sin^{2}\boldsymbol{\theta} \cdot e^{i\boldsymbol{\alpha}_{-}} + \cos^{2}\boldsymbol{\theta} \cdot e^{-i\boldsymbol{\alpha}_{-}} \end{pmatrix}$

The loss map of ITMY is not well calibrated yet.



 $loss = \sin^2 2\theta \sin^2 \alpha_-$

Measurement 10.8%

Birefringence loss can be slightly reduced by about 1% by introducing 0.5cm beam decenter.





Simulation with fixed parameters

- Add ROC to bs3
- Add tilt to bs4
- Measure p-pol power for P4



ROC m	P-pol power Finesse 2	P-pol power Finesse 3
-22020	5%	2.57%
-24890	4%	2.04%
-29060	3%	1.52%
-35970	2%	1.01%
-51400	1%	0.50%

ROC and tilt x to create different modes		P-pol power Finesse 2	P-pol power Finesse 3	
ROC (m)	-51702.6	E 0/	4.630/	
Tilt x (radian)	1.01e-06	570	4.03%	
ROC (m)	-28449.5	E 0/	2 6 6 9 /	
Tilt x (radian)	7.34e-07	570	3.00%	
ROC (m)	-22159.6	E 0/	2 60%	
Tilt x (radian)	1.35e-07	5%	2.00%	